DOCUMENT CHANGE REQUEST

DCR number 817

Changes required for: General

Originator: Steve Jeffery

Date: 2014/01/24

Date sent: 2013/09/23

Organisation: ESCC Executive

Status: IMPLEMENTED

Title:	Evaluation Test Programme for Discrete Non-Microwave Semiconductors		
Number:	2265000	Issue:	2

Other documents affected:

Page:

9, 10, 11, 13, 14, 15, 16, 21

Paragraph:

5.2, 5.4, 5.6, 5.8.2, 6, 7.3.2, 7.3.4, 7.3.5, 7.4.2, Chart I

Original wording:

See attachment (ESCC Detail Specification 2265000 Draft 3A).

Proposed wording:

See attachment (ESCC Detail Specification 2265000 Draft 3A).

Justification:

To amend, where applicable, certain test & measurement references stated in 2265000 Issue 2: these editorial changes will make the references consistent with the ESCC format of the Generic (& Detail) Specifications.

Attachments:

2265000_draft_3a.docx, null

Modifications:

N/A

Approval signature:

Date signed:

2014-01-24